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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/783,495	02/20/2004	Yung-Cheng Chen	N1085-00251 [TSMC2003-083	2148	
54657 DUANE MOR	7590 01/28/2009 RIS LLP	8	EXAMINER		
IP DEPARTMENT (TSMC)			NORTON, JENNIFER L		
30 SOUTH 17TH STREET PHILADELPHIA, PA 19103-4196			ART UNIT	PAPER NUMBER	
· .			2121		
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			MAIL DATE	DELIVERY MODE	
			01/28/2008	PAPER	

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

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Advisory Action Before the Filing of an Appeal Brief

Application No.	Applicant(s)	
10/783,495	CHEN ET AL.	-
Examiner	Art Unit	
Jennifer L. Norton	2121	

Before the iming of all Appeal Biles	Examiner	Art Unit				
	Jennifer L. Norton	2121				
The MAILING DATE of this communication appe	ears on the cover sheet with the c	correspondence add	ress			
THE REPLY FILED 02 January 2008 FAILS TO PLACE THIS	APPLICATION IN CONDITION FOR	R ALLOWANCE.				
1. The reply was filed after a final rejection, but prior to or of this application, applicant must timely file one of the follo places the application in condition for allowance; (2) a Normal Request for Continued Examination (RCE) in compliant time periods:	n the same day as filing a Notice of wing replies: (1) an amendment, aff otice of Appeal (with appeal fee) in o	Appeal. To avoid aba fidavit, or other evider compliance with 37 C	nce, which FR 41.31; or (3)			
a) The period for reply expiresmonths from the mailir	og date of the final rejection	•				
b) The period for reply expires on: (1) the mailing date of this no event, however, will the statutory period for reply expire	Advisory Action, or (2) the date set forth later than SIX MONTHS from the mailin	g date of the final reject	ion.			
Examiner Note: If box 1 is checked, check either box (a) or TWO MONTHS OF THE FINAL REJECTION. See MPEP 7	706.07(f).					
Extensions of time may be obtained under 37 CFR 1.136(a). The date have been filed is the date for purposes of determining the period of exunder 37 CFR 1.17(a) is calculated from: (1) the expiration date of the set forth in (b) above, if checked. Any reply received by the Office late may reduce any earned patent term adjustment. See 37 CFR 1.704(b) NOTICE OF APPEAL	xtension and the corresponding amount shortened statutory period for reply orig er than three months after the mailing da	of the fee. The approprinally set in the final Offi	iate extension fee ce action; or (2) as			
 The Notice of Appeal was filed on A brief in com filing the Notice of Appeal (37 CFR 41.37(a)), or any external a Notice of Appeal has been filed, any reply must be filed AMENDMENTS 	ension thereof (37 CFR 41.37(e)), to	avoid dismissal of th				
 The proposed amendment(s) filed after a final rejection, (a) They raise new issues that would require further common to the proposed amendment (s). 	onsideration and/or search (see NO		ecause			
(b) They raise the issue of new matter (see NOTE below)		duaine as aisealificina	the income for			
(c) They are not deemed to place the application in be appeal; and/or	etter form for appear by materially re	ducing or simplifying	the issues to			
(d) They present additional claims without canceling a NOTE: (See 37 CFR 1.116 and 41.33(a))		ected claims.				
4. The amendments are not in compliance with 37 CFR 1.		ompliant Amendment	(PTOL-324). 😁			
5. Applicant's reply has overcome the following rejection(s			មកជាដ្ឋា			
 Newly proposed or amended claim(s) would be a non-allowable claim(s). 	allowable if submitted in a separate,	timely filed amendme	ent canceling the			
7. For purposes of appeal, the proposed amendment(s): a) how the new or amended claims would be rejected is proof the status of the claim(s) is (or will be) as follows: Claim(s) allowed:		II be entered and an e	explanation of the			
Claim(s) objected to:						
Claim(s) rejected:	·		in in Kompania (A)			
Claim(s) withdrawn from consideration: AFFIDAVIT OR OTHER EVIDENCE			Map			
 The affidavit or other evidence filed after a final action, b because applicant failed to provide a showing of good at was not earlier presented. See 37 CFR 1.116(e). 						
9. The affidavit or other evidence filed after the date of filing entered because the affidavit or other evidence failed to showing a good and sufficient reasons why it is necessa	overcome all rejections under appe	al and/or appellant fa	will <u>not</u> be ils to provide a			
10. ☐ The affidavit or other evidence is entered. An explanation REQUEST FOR RECONSIDERATION/OTHER	•					
11. ☑ The request for reconsideration has been considered but does NOT place the application in condition for allowance because; <u>See Continuation Sheet.</u>						
12. Note the attached Information Disclosure Statement(s).	(PTO/SB/08) Paper No(s)		\mathcal{N}_{i}			
13. Other:	_	7.				
	DAY.	Y PATENT EXAMIN	17/09			
*	SUPERVISOR	Y PATENT EXAMIN	IER			
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Continuation of 11. does NOT place the application in condition for allowance because: Applicant's arguments, see Remarks pgs. 2-7, ... filed 02 January 2008 with respect to claims 1-22 under 35 U.S.C. 103(a) have been fully considered but they are not persuasive.

With respect to the Applicant's arguments that the prior art teaches away from Applicant's system; the Examiner respectfully disagrees. See MPEP 2123, recited below for convenience:

MPEP 2123 states:

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"Disclosed examples and preferred embodiments do not constitute a teaching away from a broader disclosure or nonpreferred embodiments. In re Susi, 440 F.2d 442, 169 USPQ423 (CCPA 1971). "A known or obvious composition does not become patentable simply because it has been described as somewhat inferior to some other product for the same use." In re Gurley, 27 F.3d 551, 554, 31 USPQ2d 1130, 1132 (Fed. Cir. 1994) (The invention was directed to an epoxy impregnated fiber-reinforced printed circuit material. The applied prior art reference taught a printed circuit material similar to that of the claims but impregnated with polyesterimide resin instead of epoxy. The reference, however, disclosed that epoxy was known for this use, but that epoxy impregnated circuit boards have "relatively acceptable dimensional stability" and "some degree of flexibility," but are inferior to circuit boards impregnated with polyesterimide resins. The court upheld the rejection concluding that applicant's argument that the reference teaches away from using epoxy was insufficient to overcome the rejection since "Gurley asserted no discovery beyond what was known in the art." 27 F.3d at 554, 31 USPQ2d at 1132.). Furthermore, "[t]he prior art's mere disclosure of more than one alternative does not constitute a teaching away from any of these alternatives because such disclosure does not criticize, discredit, or otherwise discourage the solution claimed...." In re Fulton,391 F.3d 1195, 1201, 73 USPQ2d 1141, 1146 (Fed. Cir. 2004)."

Incregards to Applicant's argument that U.S. Patent Publication No. 2004/0092047 (hereinafter Lymberopoulous) does not teach, "using a CD measurement to control exposure energy", the Examiner recognizes the Applicant has not accounted for the combination of U.S. Patent No. 5,409,538 (hereinafter Nakayama) and Lymberopoulous under 35 U.S.C 103(a) for this limitation as set forth in the Final Office Action, mailed on 05 November 2007.

With respect to the Applicant's arguments that it would not have been obvious to combine the prior art of Nakayama and Lymberopoulous; the Examiner respectfully disagrees.

Nakayama teaches controlling the exposure energy with a feedback process control signal (col. 6, lines 14-20 and 48-55, col. 15, lines 12-21 and Fig. 18), and controlling the exposure energy with a feed forward process control signal of a compensation amount that compensates for wafer thickness variations (col. 6, lines 48-55 and col. 15, lines 14-41, i.e. "the results of the correction"). Nakayama further teaches, measuring optical properties of a film such as reflectivity, refractive index, transmittance, polarization, spectral transmittance, and absorption coefficient" (As indicated by the Applicant on pg. 2, lines 24-26 of the Remarks).

Lymberopoulous teaches to a patterned wafer substrate (pg. 3, par. [0028]), a wafer measuring tool where the CD is optically measured on a patterned photoresist layer (pg. 4, par. [0036]) and critical dimension being one of a width, a spacing and an opening of the patterned wafer substrate (pg. 1, par. [0007]).

Therefore, it would have been obvious to a person of ordinary skill in the art at the time of applicant's invention to modify the teaching of Nakayama to include a patterned wafer substrate, a wafer measuring tool where the CD is optically measured on a patterned photoresist layer and critical dimension being one of a width, a spacing and an opening of the patterned wafer substrate to provide a simple, cost effective methodology for fast and meaningful identification and correction of CD variation without significantly compromising throughput (pg. 2, par. [0013]).

Hence, claims 1-22 stand rejected under 35 U.S.C. 103(a) as set forth in the Final Office Action mailed on 05 November 2007.